IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

NCR Corporation Docket No. 10994

In re application of: DURRANT, D. J. et al.

Serial No. 09/541,137

Filed: March 31, 2000

For: METHOD AND SYSTEM FOR IDENTIFYING MANUFACTURING ANOMALIES IN A MANUFACTURING SYSTEM

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

Transmitted herewith is an amendment in the above-identified application.

☒ No additional fee is required.

The fee has been calculated as shown below:

CLAIMS AS AMENDED

FOR	Claims Remaining After Amendment		Highest Number Previously Paid For	Extra Present	Rate	Additional Fee
Total Claims	12	-	20	0 X	$ 18 =	$ 0
Independent Claims	2	-	3	0 X	$ 84 =	$ 0
Total additional fee for this amendment ----->						$ 0

* If the entry in Column 2 is less than the entry in Column 4, write "0" in Column 5.

** If the "Highest Number Previously Paid For" in this space is less than 20, write "20" in this space.

*** If the "Highest Number Previously Paid For" in this space is less than 3, write "3" in this space.

☐ Please charge the above fee to the account of NCR Corporation, Deposit Account No. 50-1673.

Respectfully,

James M. Stover
Reg. No. 32,759

CERTIFICATION OF MAILING UNDER 37 CFR 1.8

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231 on January 27, 2003

By: Sallie Spicer

Name: Sallie Spicer

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Dayton, Ohio

Docket No. 10994

Application of:

DURRANT, D. J. et al.   Group Art Unit: 2125

Serial No. 09/541,137   Examiner: RAO, SHEELA S.

Filed: March 31, 2000

For: **METHOD AND SYSTEM FOR IDENTIFYING MANUFACTURING ANOMALIES IN A MANUFACTURING SYSTEM**

Assistant Commissioner for Patents

Washington, D.C.   20231

RESPONSE

Sir:

The following remarks are presented in response to the Official Action dated September 26, 2002, wherein the Examiner rejected claims 1 through 12 of the present application under 35 U.S.C. 102(e) as being anticipated by U.S. Patent No. 6,301,517 issued to Doran et al. Claims 1 through 12 of the present application are provided in an appendix to this response.

Doran et al. discloses an automated monitoring and notification system for identifying potentially faulty test sockets within a test system and notify the proper user of the location of these potentially faulty test sockets. The system described

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January 27, 2003

By: _____

Name: Sallie T. Spicer

at column 3, lines 29-42, of Doran et al. includes a manufacturing database that stores test data associated with each test socket. Failure rate information for each socket obtained from the manufacturing database is compared against a predetermined threshold to identify potentially faulty test sockets.
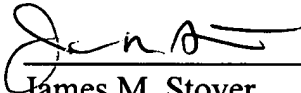
Clearly, the invention as described and claimed in the present application differs from the system taught in Doran et al. The manufacturing database of Doran et al. stores test data for test sockets. The system and method described in the present application does not store data associated with test sockets. The system and method described in the present application stores product manufacturing parameters within a database, analyzes the stored product manufacturing parameters to define one or more normal parameter subsets, and detects manufacturing parameters that are not contained within a normal subset in order to identify manufacturing anomalies.

Examples of manufacturing parameters provided in the present application include: the tolerance of a lot of resistors, the threshold of a lot of resistors, the capacitance of a lot of capacitors, the reactance of a lot of capacitors, the supplier from which a lot originated, the shipping method used for transporting a lot of components, and the time of year that a lot of components was manufactured. Socket test data is plainly different from manufacturing parameters, as these examples illustrate.

It is believed that the claims of the present application are patentable over the cited reference to Doran et al. Doran et al does not teach or suggest a system that stores product manufacturing parameters within a database, analyzes the stored product manufacturing parameters to define one or more normal parameter subsets, and detects manufacturing parameters that are not contained within a normal subset in order to identify manufacturing anomalies.

Review and reconsideration of the present application is respectfully requested.

Respectfully submitted,

James M. Stover
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